

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of)
)
Patrick P. Naulleau) Group Art Unit:
)
Application No.:) Examiner:
)
Filed: August 30, 2001)
)
For: APPARATUS FOR GENERATING PARTIALLY)
COHERENT RADIATION)



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3/27/00
M. P. Radjen

INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner for Patents
Washington, D.C. 20231

Sir:

In accordance with the duty of disclosure as set forth in 37 C.F.R. § 1.56, Applicant hereby submits the following information in conformance with 37 C.F.R. §§ 1.97 and 1.98. Pursuant to 37 C.F.R. § 1.98, a copy of each of the documents cited is enclosed.

U.S. Patent No. 5,510,230, Tennant et al., issued 04-23-1996

U.S. Patent No. 5,512,759, Sweatt, issued 04-30-1996

U.S. Patent No. 5,920,380, Sweatt, issued 07-06-1999

U.S. Patent No. 6,033,079, Hudyma, issued 03-07-2000

U.S. Patent No. 6,072,852, Hudyma, issued 06-06-2000

U.S. Patent No. 6,084,938, Hara et al., issued 07-04-2000

U.S. Patent No. 6,183,095, Hudyma, issued 02-06-2001

U.S. Patent No. 6,188,513, Hudyma, issued 02-13-2001

U.S. Patent No. 6,198,793, Schultz et al., issued 03-06-2001

U.S. Patent No. 6,226,346, Hudyma, issued 05-01-2001

U.S. Patent No. 6,262,836, Hudyma et al., issued 07-17-2001

Naulleau, P. et al., "Characterization of the accuracy of EUV phase-shifting point diffraction interferometry", *SPIE*, vol. 3331, pp. 114-123; and

White, D.L. et al., "Modification of the coherence of undulator radiation", *Rev. Sci. Instrum.*, 66 (2), Feb. 1995, pp. 1930-1933

The documents are being submitted within 3 months of the filing or entry of the national stage of this application or before the first Office Action on the merits, whichever is later, therefore no fee or certification is required under 37 C.F.R. § 1.97(b).

To assist the Examiner, the documents are listed on the attached form PTO-1449. It is respectfully requested that an Examiner initialed copy of this form be returned to the undersigned.

Respectfully submitted,

BURNS, DOANE, SWECKER & MATHIS, L.L.P.

By: 

Charles H. Jew
Registration No. 34,192

P.O. Box 1404
Alexandria, Virginia 22313-1404
(650)622-2300

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Substitute for form 1449A/PTO

ATTORNEY'S DKT NO.
015780-041 (CIB-1660)

APPLICATION NO.

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

 APPLICANT
 Patrick P. Naulleau
 FILING DATE
 August 30, 2001

GROUP

 J1035 U.S. PTO
 09/944391

08/30/01

U.S. PATENT DOCUMENTS

Examiner Initials	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication (MM-DD-YYYY)
	Number	Kind Code (if known)		
	5,510,230		Tennant et al.	04-23-1996
	5,512,759		Sweatt	04-30-1996
	5,920,380		Sweatt	07-06-1999
	6,033,079		Hudyma	03-07-2000
	6,072,852		Hudyma	06-06-2000
	6,084,938		Hara et al.	07-04-2000
	6,183,095		Hudyma	02-06-2001
	6,188,513		Hudyma	02-13-2001
	6,198,793		Schultz et al.	03-06-2001
	6,226,346		Hudyma	05-01-2001
	6,262,836		Hudyma et al.	07-17-2001

FOREIGN PATENT DOCUMENTS

Examiner Initials	Foreign Patent Document		Country	Date of Publication (MM-DD-YYYY)	Translation	
	Number	Kind Code (if known)			Yes	no

NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Include name of author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
	Naulleau, P. et al., "Characterization of the accuracy of EUV phase-shifting point diffraction interferometry", <i>SPIE</i> , vol. 3331, pp. 114-123
	White, D.L. et al., "Modification of the coherence of undulator radiation", <i>Rev. Sci. Instrum.</i> , 66 (2), Feb. 1995, pp. 1930-1933
Examiner Signature	Date Considered

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. SEND TO: Assistant Commissioner for Patents, Washington, D.C. 20231.